

## 30V N+P-Channel Enhancement Mode MOSFET

### Description

The AP50G03GD uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 30V$   $I_D = 52A$

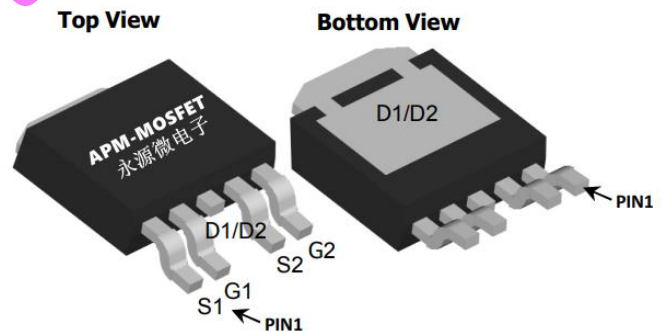
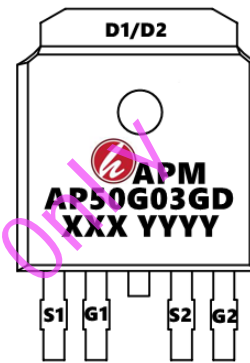
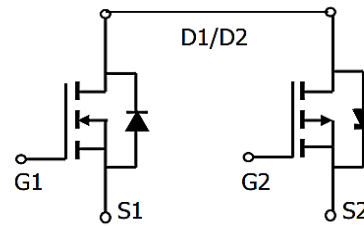
$R_{DS(ON)} < 10m\Omega$  @  $V_{GS}=10V$  (Type: 7.2m $\Omega$ )

$V_{DS} = -30V$   $I_D = -48A$

$R_{DS(ON)} < 13m\Omega$  @  $V_{GS}=-10V$  (Type: 8.8m $\Omega$ )

### Application

BLDC



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP50G03GD	TO-252-4L	AP50G03GD XXX YYYY	2500

### Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	N-Ch	P-Ch	Units
$V_{DS}$	Drain-Source Voltage	30	-30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	$\pm 20$	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	52	-48	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	38.5	-37.5	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	150	-144	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	289	378	mJ
$I_{AS}$	Avalanche Current	28	29.5	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation <sup>4</sup>	46	41.3	W
$T_{STG}$	Storage Temperature Range	-55 to 150	-55 to 150	$^\circ C$
$T_J$	Operating Junction Temperature Range	-55 to 150	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	62.5		$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	2.3		$^\circ C/W$

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### N-Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30	33	---	V
ΔBVDSS/ΔT <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	---	0.0193	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A	---	7.2	10	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	---	11	16	
VGS(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2	1.6	2.5	V
ΔVGS(th)	V <sub>GS(th)</sub> Temperature Coefficient		---	-3.97	---	mV/°C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	---	---	1	uA
		V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	---	---	±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =30A	---	34	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	---	1.8	---	Ω
Q <sub>g</sub>	Total Gate Charge (4.5V)	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	---	9.8	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	4.2	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	3.6	---	
Td(on)	Turn-On Delay Time	V <sub>DD</sub> =15V, V <sub>GS</sub> =10V, R <sub>G</sub> =3.3Ω I <sub>D</sub> =15A	---	4	---	ns
T <sub>r</sub>	Rise Time		---	8	---	
Td(off)	Turn-Off Delay Time		---	31	---	
T <sub>f</sub>	Fall Time		---	4	---	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	---	940	---	pF
C <sub>oss</sub>	Output Capacitance		---	131	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	109	---	
I <sub>s</sub>	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	---	---	43	A
ISM	Pulsed Source Current <sup>2,5</sup>		---	---	112	A
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =1A, T <sub>J</sub> =25°C	---	---	1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=30A, dI/dt=100A/μs, T <sub>J</sub> =25°C	---	8.5	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	2.2	---	nC

#### Note :

- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- The EAS data shows Max. rating. The test condition is VDD=25V, VGS=10V, L=0.1mH, IAS=28A
- The power dissipation is limited by 175°C junction temperature
- The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

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### P-Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> = -250μA	-30	-32.5	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> =0V,	-	-	-1	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.2	-1.5	-2.5	V
RDS(on)	Static Drain-Source on-Resistance note3	V <sub>GS</sub> = -10V, I <sub>D</sub> = -10A	-	8.8	13	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	-	16	20	
Rg	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	4.9	7.0	9.1	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -24V, V <sub>GS</sub> =10V, f=1.0MHz	-	2130	-	pF
C <sub>oss</sub>	Output Capacitance		-	280	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	252	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -24V, I <sub>D</sub> = -1A, V <sub>GS</sub> = -10V	-	22	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	4	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	5.8	-	nC
td(on)	Turn-on Delay Time	V <sub>DD</sub> = -24V, I <sub>D</sub> = -1A, V <sub>GS</sub> = -10V, R <sub>GEN</sub> =7.0Ω	-	9	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	13	-	ns
td(off)	Turn-off Delay Time		-	48	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	20	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-29.5	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-44	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> = -1A	-	-0.74	-1.2	V

**Note :**

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
3. The power dissipation is limited by 175°C junction temperature
4. EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>= -24V, V<sub>G</sub>= -10V, R<sub>G</sub>=7Ω, L=0.1mH, I<sub>AS</sub>= -29.5A
5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

### N-Typical Characteristics

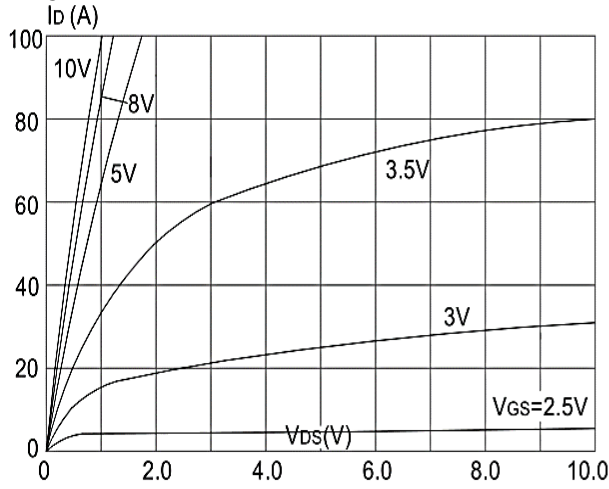


Figure 1: Output Characteristics

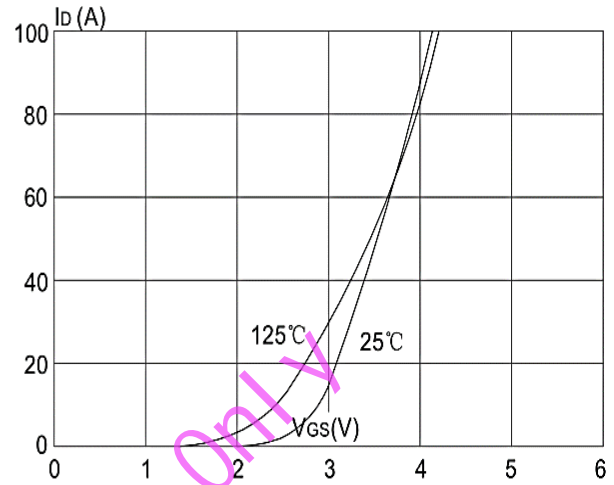


Figure 2: Typical Transfer Characteristics

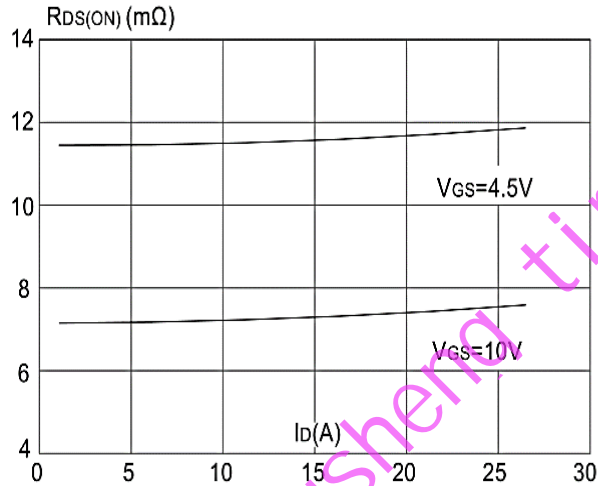


Figure 3: On-resistance vs. Drain Current

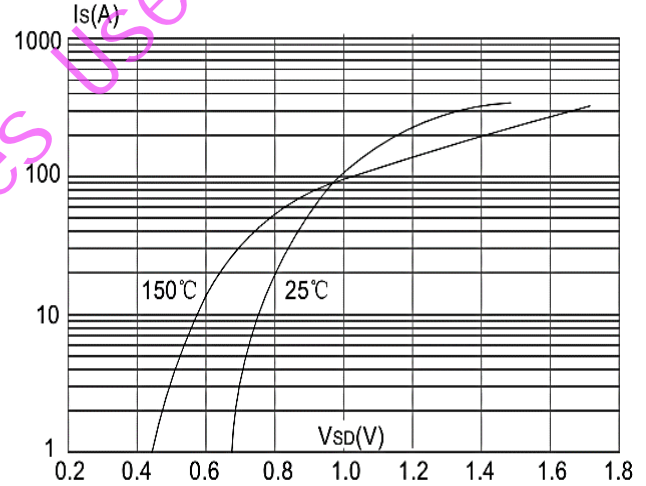


Figure 4: Body Diode Characteristics

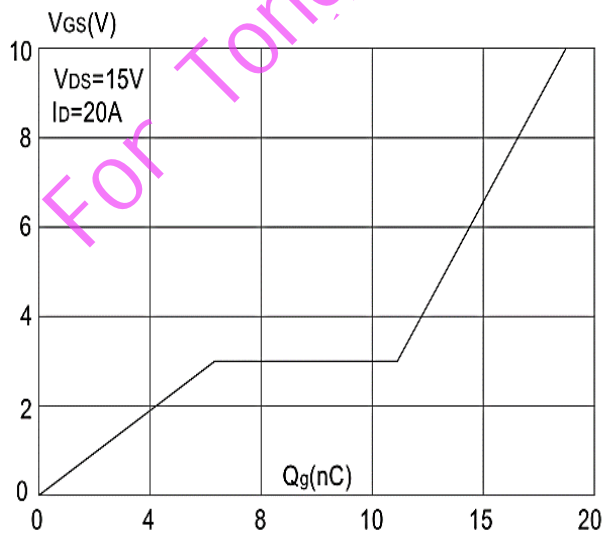


Figure 5: Gate Charge Characteristics

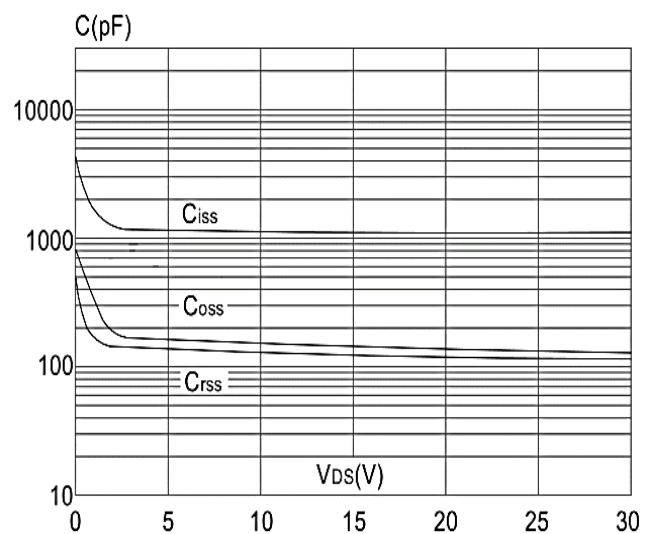


Figure 6: Capacitance Characteristics

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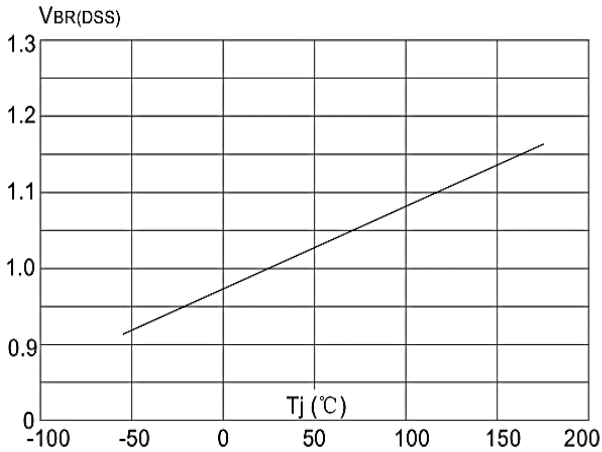


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

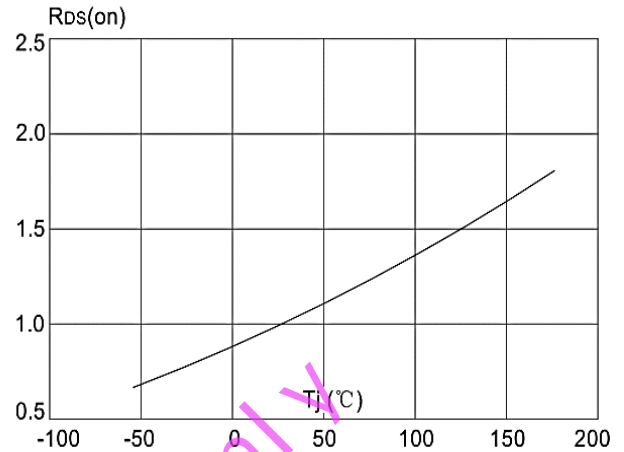


Figure 8: Normalized on Resistance vs. Junction Temperature

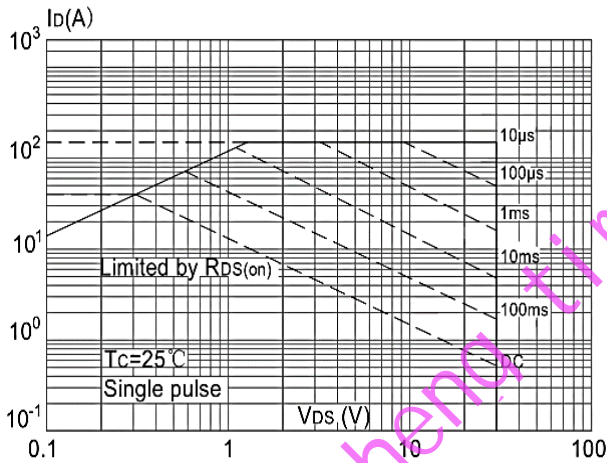


Figure 9: Maximum Safe Operating Area Temperature

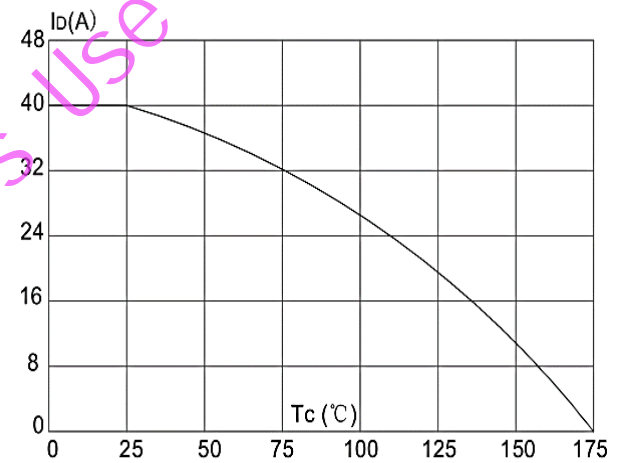


Figure 10: Maximum Continuous Drain Current vs. Ambient

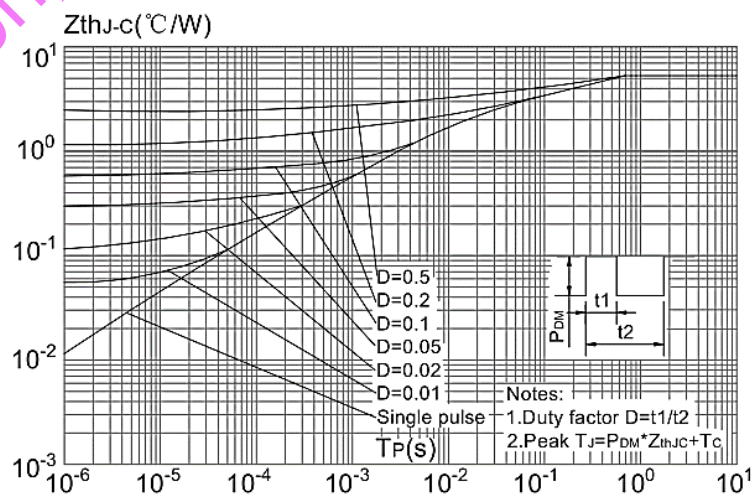


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

### P-Typical Characteristics

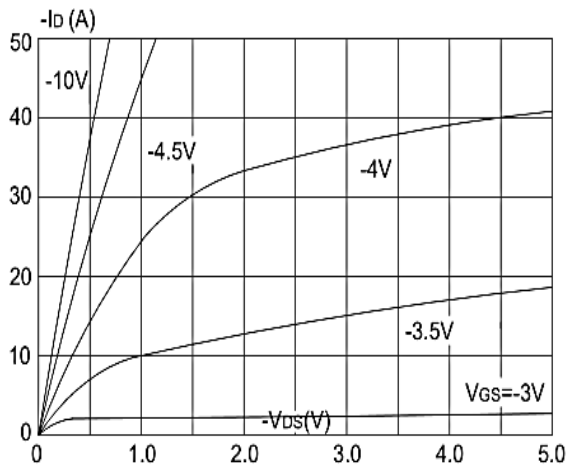


Figure1: Output Characteristics Figure

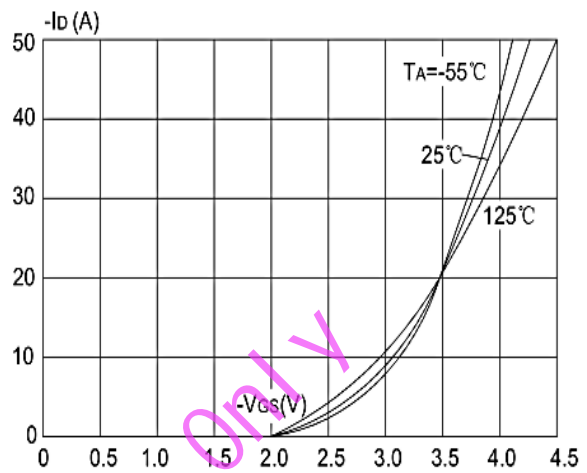


Figure2: Typical Transfer Characteristics

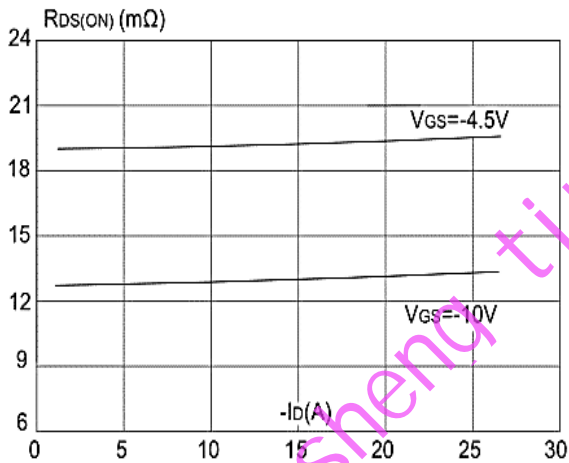


Figure 3: On-resistance vs. Drain Current

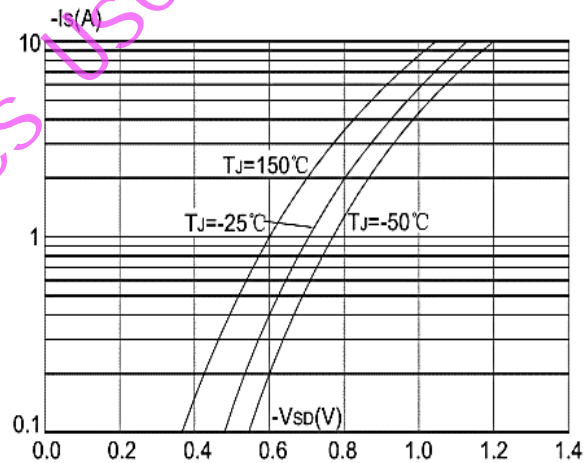


Figure 4: Body Diode Characteristics

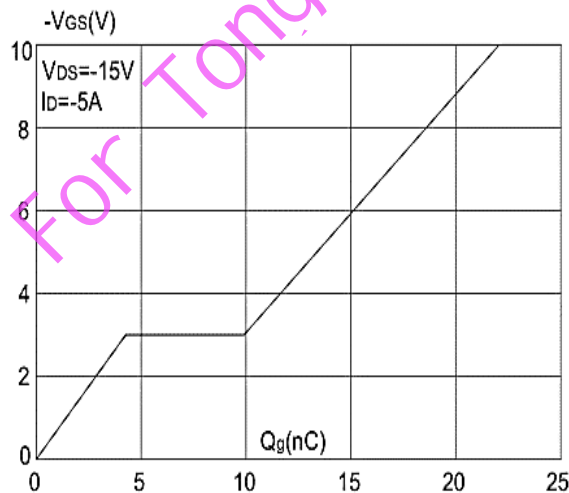


Figure 5: Gate Charge Characteristics

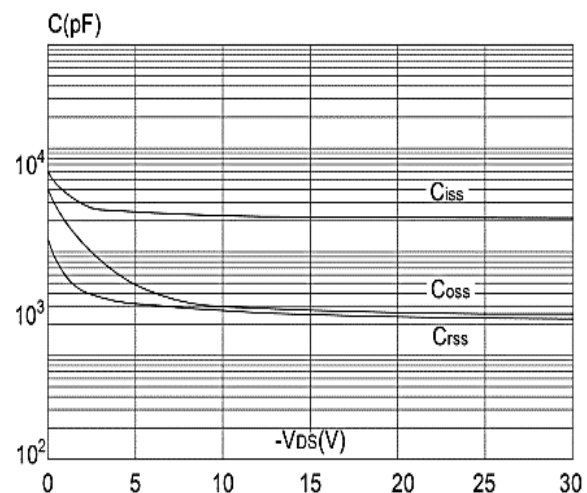


Figure 6: Capacitance Characteristics



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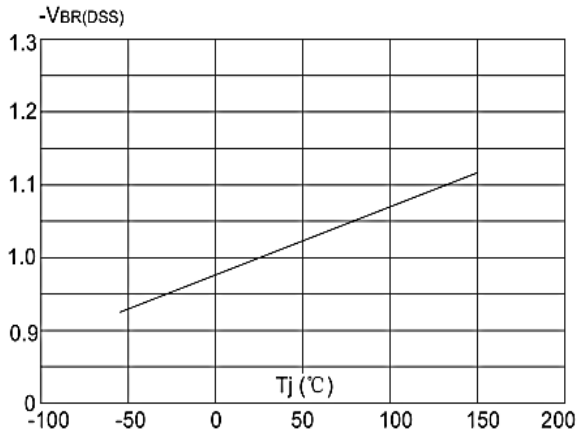


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

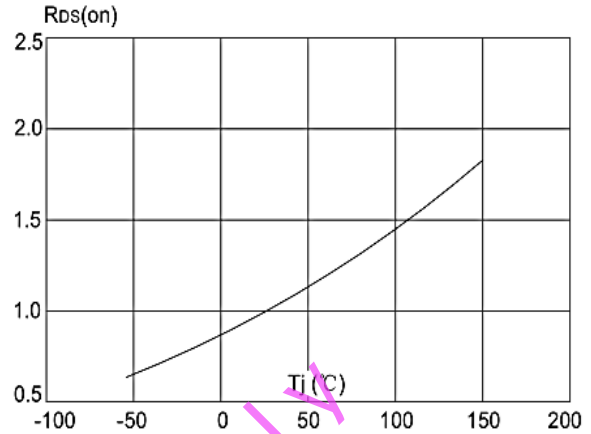


Figure 8: Normalized on Resistance vs. Junction Temperature

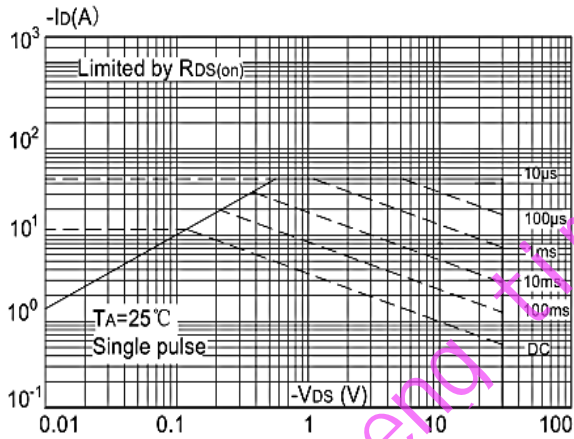


Figure 9: Maximum Safe Operating Area

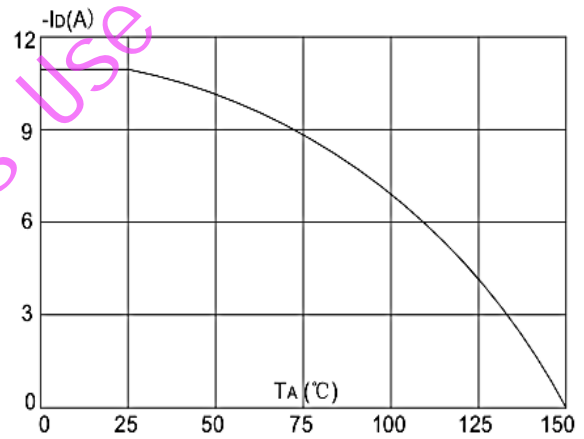


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

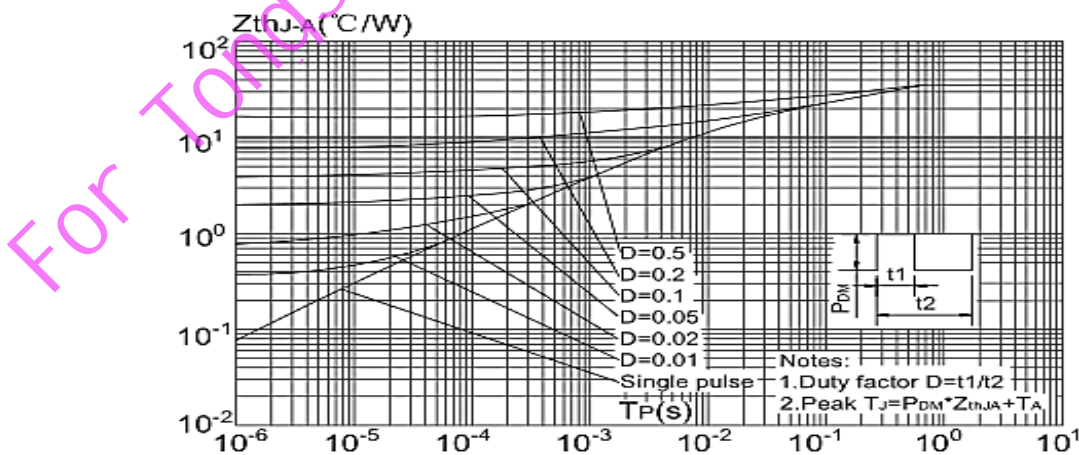
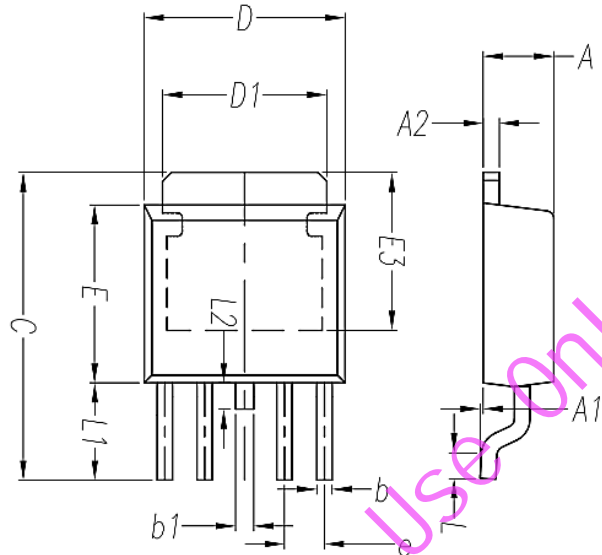


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



**Package Mechanical Data-TO-252-4L-Duble-DX**



Symbol	Common		
	mm		
	Mim	Nom	Max
D	6.30	6.55	6.80
D1	4.80	5.35	5.90
C	9.70	10.00	10.30
E	5.90	6.10	6.30
E3	4.50	5.15	5.80
L	0.90	1.35	1.80
L1	2.60	2.85	3.05
L2	0.50	0.85	1.20
b	0.30	0.50	0.70
b1	0.40	0.60	0.80
A	2.10	2.30	2.50
A2	0.40	0.53	0.65
A1	0.00	0.10	0.20
e	1.17	1.27	1.37



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